

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Measuring method for semiconductor infrared-emitting diode -
Part 14: Junction temperature**

半导体红外发射二极管测量方法 第14部分：结温

(English Translation)

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What this standard covers

This standard specifies the measurement principle diagram, measurement procedure and specified conditions for the junction temperature of semiconductor infrared emitting diodes. Suitable for semiconductor infrared emitting diodes.

Document data

Chinese classification (CCS): L53.

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